Applicant(s)/Patent Under Application/Control No. Reexamination 10/763,166 ONO ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Peter Lee 2852 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-2002/0181979 A1 12-2002 Fukutome, Yasuyuki 399/329 Α US-4,682,878 07-1987 399/122 В Takizawa et al. US-С US-D US-Ε US-F US-G US-Н US-US-J Κ US-US-L US-М FOREIGN PATENT DOCUMENTS Date **Document Number** Country Name Classification Country Code-Number-Kind Code MM-YYYY N 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧ W

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